

Notice of References Cited	Application/Control No. 10/679,755		Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Khai M. Nguyen		Art Unit 2819	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,703,959	03-2004	Kuwabara, Takao	341/155
*	B	US-6,747,695	06-2004	Afghahi, Morteza	348/241
*	C	US-5,317,406	05-1994	Kobayashi et al.	348/307
*	D	US-6,483,541	11-2002	Yonemoto et al.	348/302
*	E	US-5,708,471	01-1998	Okumura, Fujio	348/301
*	F	US-6,133,862	10-2000	Dhuse et al.	341/118
*	G	US-6,366,312	04-2002	Crittenden, Brent S.	348/187
*	H	US-6,734,897	05-2004	Mentzer, Ray A.	348/180
*	I	US-5,877,715	03-1999	Gowda et al.	341/122
*	J	US-6,642,494	11-2003	Endo, Tadao	250/208.1
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.